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<u>L31</u>	L27 and least same squares	16	<u>L31</u>
<u>L30</u>	L27 and math\$ same assumption	4	<u>L30</u>
<u>L29</u>	L28 and math\$ same assumption	4	<u>L29</u>
<u>L28</u>	L27 and rules	33	<u>L28</u>
<u>L27</u>	correlat\$ near (datasets or data with sets)	177	<u>L27</u>
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<u>L26</u>	4736347.pn.	.1	<u>L26</u>
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<u>L25</u>	L24 and errors	14	<u>L25</u>
<u>L24</u>	L23 and fit\$ near3 procedures	15	<u>L24</u>
<u>L23</u>	L22 and least near3 squares	832	<u>L23</u>
<u>L22</u>	L21 and (inverse or reverse)	5806	<u>L22</u>
<u>L21</u>	L20 and matrix	11244	<u>L21</u>
<u>L20</u>	(data near analysis or data near mining)	43548	<u>L20</u>

<u>L19</u>	L18 and least near3 squares	9	<u>L19</u>
<u>L18</u>	actuarial same analysis	106	<u>L18</u>
<u>L17</u>	705/10	2374	<u>L17</u>
<u>L16</u>	705/1	4780	<u>L16</u>
<u>L15</u>	345/721	267	<u>L15</u>
<u>L14</u>	725/42	183	<u>L14</u>
<u>L13</u>	725/100	245	<u>L13</u>
<u>L12</u>	725/14	276	<u>L12</u>
<u>L11</u>	725/1	332	<u>L11</u>
<u>L10</u>	345/721	267	<u>L10</u>
<u>L9</u>	709/217	5437	<u>L9</u>
<u>L8</u>	709.clas.	29703	<u>L8</u>
<u>L7</u>	345.clas.	68637	<u>L7</u>
<u>L6</u>	348.clas.	62417	<u>L6</u>
<u>L5</u>	725.clas.	9477	<u>L5</u>
<u>L4</u>	707.clas.	21301	<u>L4</u>
<u>L3</u>	707/104.1	4279	<u>L3</u>
<u>L2</u>	707/10	8673	<u>L2</u>
<u>L1</u>	707/9	2204	<u>L1</u>

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